SCAS029A - JULY 1987 - REVISED APRIL 1993

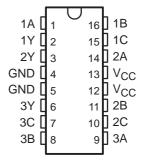
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configuration Minimizes High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

description

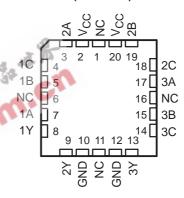
These devices contain three independent 3-input AND gates. They perform the Boolean functions $Y = A \cdot B \cdot C$ or $Y = \overline{A} + \overline{B} + \overline{C}$ in positive logic.

The 54AC11011 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74AC11011 is characterized for operation from -40°C to 85°C.

54AC11011 . . . J PACKAGE 74AC11011 . . . D OR N PACKAGE (TOP VIEW)



54AC11011 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

FUNCTION TABLE (each gate)

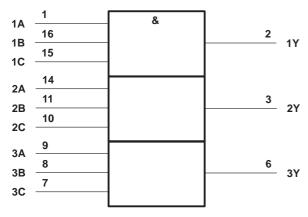
	(9	7
	INPUTS	OUTPUT	
Α	В	С	Y
Н	Н	Н	Н
L	X	Χ	L
Х	L	Χ	L
Х	X	L	L

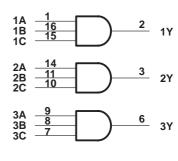
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logic symbol†

logic diagram (positive logic)





Pin numbers shown are for the D, J, and N packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		-0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, IOK (VO < 0 or VO >	V _{CC})	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_O$	CC)	±50 mA
Continuous current through V _{CC} or GND .		±100 mA
Storage temperature range		65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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recommended operating conditions

			54	AC1101	1	74AC11011			UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
VCC	Supply voltage		3	5	5.5	3	5	5.5	V	
		V _{CC} = 3 V	2.1			2.1				
V_{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V	
		$V_{CC} = 5.5 \text{ V}$	3.85			3.85				
		V _{CC} = 3 V			0.9			0.9		
VIL	Low-level input voltage	V _{CC} = 4.5 V			1.35			1.35	V	
		V _{CC} = 5.5 V			1.65			1.65		
٧ _I	Input voltage		0		VCC	0		VCC	V	
٧o	Output voltage		0		VCC	0		VCC	V	
		V _{CC} = 3 V			-4			-4		
ЮН	High-level output current	V _{CC} = 4.5 V			-24			-24	mA	
		V _{CC} = 5.5 V			-24			-24		
		VCC = 3 V		.0	12			12		
IOL	Low-level output current	V _{CC} = 4.5 V		2 /5	24			24	mA	
		V _{CC} = 5.5 V	3.0	4	24			24		
Δt/Δν	Input transition rise or fall rate	- Gc	0	(C)	10	0		10	ns/V	
TA	Operating free-air temperature	4 %	-55	100	125	-40		85	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	V	T _A = 25°C			54AC1	1011	74AC1	LINIT	
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		3 V	2.9			2.9		2.9		
	$I_{OH} = -50 \mu\text{A}$	4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
Vou	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.4		2.48		\ \/
VOH	044	4.5 V	3.94			3.7		3.8		V
	I _{OH} = – 24 mA	5.5 V	4.94			4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
	I _{OL} = 50 μA	3 V			0.1		0.1		0.1	
		4.5 V			0.1		0.1		0.1	
		5.5 V			0.1		0.1		0.1	
VOL	I _{OL} = 12 mA	3 V			0.36		0.5		0.44	V
VOL	I _{OL} = 24 mA	4.5 V			0.36		0.5		0.44	
	IOL - 24 IIIA	5.5 V			0.36		0.5		0.44	
	I _{OL} = 50 mA [†]	5.5 V					1.65			
	I _{OL} = 75 mA [†]	5.5 V							1.65	
lį	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μΑ
Ci	V _I = V _{CC} or GND	5 V		3.5						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



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switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	4 = 25°C	;	54AC1	11011	74AC1	1011	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	Any	V	1.5	6	8.3	1.5	9.7	1.5	9.1	20
^t PHL	Any	Y	1.5	6	8.2	1.5	9.6	1.5	9	ns

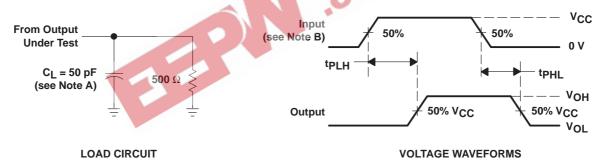
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	FROM TO (OUTPUT)	T _A = 25°C		54AC11011		74AC11011		UNIT	
PARAMETER	(INPUT)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
t _{PLH}	Any	Υ	1.5	4	5.9	1.5	6.9	1.5	6.5	no
t _{PHL}			1.5	4.5	6.4	1.5	7.3	1.5	6.9	ns

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per gate	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	28	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \ \Omega$, $t_f = 3 \ ns$, $t_f = 3 \ ns$.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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